	Application No.	Applicant(s)
	09/941,853	CANELLA, ROBERT L.
Notice of Allowability	Examiner	Art Unit
	Evan Pert	2826
The MAILING DATE of this communication apperature All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RI of the Office or upon petition by the applicant. See 37 CFR 1.313	(OR REMAINS) CLOSED in this ap or other appropriate communication GHTS. This application is subject t	plication. If not included n will be mailed in due course. THIS
1. This communication is responsive to the RCE filed August 18, 2003.		
2. The allowed claim(s) is/are <u>1,3,5,7-18,20-26,44-55,66 and 67.</u>		
3. The drawings filed on 8-18-03 (with 6-14-02) are accepted by the Examiner.		
 4.		
 Attachment(s) 1. ☑ Notice of References Cited (PTO-892) 2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948) 3. ☑ Information Disclosure Statements (PTO-1449 or PTO/SB/0 Paper No./Mail Date 0305 & 0605 4. ☐ Examiner's Comment Regarding Requirement for Deposit of Biological Material 	6. ☐ Interview Summary Paper No./Mail Da 8), 7. ☐ Examiner's Amendo	ite .

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DETAILED ACTION

Allowable Subject Matter

1. Claims 1, 3, 5, 7-18, 20-26, 44-55, and 66-67 (renumbered as claims 1-36) are allowed.

2. The following is an examiner's statement of reasons for allowance:

The prior art does not disclose applicant's claimed substrate assembly or electrical component, characterized by, in the context of *all* the claim limitations, for example, by a "spring-biased electrical contact that may be deflected into a via disposed at a location aligned with the spring-biased electrical contact," or "a plurality of vias opening onto a surface of a substrate and comprising a recess into which one of the spring-biased contacts may be deflected," or that a "spring-biased contact," in the context of the totality of claim limitations, includes a "contact element" which is "configured to remove or puncture through a layer of contaminants formed on an exterior surface of a lead element extending from an IC device, the contact element comprising a plurality of alternating grooves or ridges, a plurality of protrusions, or a roughened surface."

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

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Conclusion

3. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure:

Perhaps Kohn et al. is the closest art cited by the examiner in this Office Action, yet in the Kohn et al. reference, while deflection of a contact is into a recess (cavity), the recess/cavity is not "disposed at a location aligned" with a via and/or the via does not "open onto a surface of the substrate and comprising a recess (into which deflection of the contact occurs)," as is claimed by applicant.

4. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Evan Pert whose telephone number is 571-272-1969.

The examiner can normally be reached on M-F (7:30AM-3:30 PM).

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Nathan Flynn can be reached on 571-272-1915. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

EVAN PERT PRIMARY EXAMINER

ETP August 20, 2005